Development of an SDD-based detection chain irfu for the Chinese eXTP X-ray astronomy mission



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CONTEXT

The eXTP (Enchanced X-ray Timing and Polarimetry) mission

- Future X-ray astronomy satellite
- Objectives: solve fundamental physics questions especially study the behavior of ultra-dense matter and matter in strong gravity and intense electromagnetic fields.
- Means: observe various classes of compact objects (e.g. neutron stars, black holes, etc.) to study the fine temporal variations in their X-ray spectrum and polarization.

The scientific case and the payload are developed by a Sino-European Scientific Consortium led

RESULTS

Electricals tests





Vers ASIC daughter board Fig. 5: Test Setup for electrical tests $ENC^{2} = \frac{\alpha \times (C_{tot})^{2}}{T_{peak}} + \beta \times (C_{tot})^{2} + \gamma \times \frac{2 \times I_{leak} \times T_{peak}}{a}$ With: ENC=f(Tpeak) - Tpeak: the peaking time, time from 1% to 99% of the signal β , γ : three variables extracted from α, measurements: $\alpha \times (C_{tot})^2 = 228*10^{-6} \text{ el}^2.\text{s}^{-1}$ $\beta \times (C_{tot})^2 = 59 \text{ el}^2$ $\gamma = 1,53$ C_{tot} : the total capacitance - I_{leak} the leakage current

q is the elementary charge

Fig. 6: Noise measurements with different leakage current values and ENC modeling (average noise of



Noise performance in

LAD : Large Array Detector

40 modules

DESIGN

all channels). 0.75 1.00 1.25 1.50 1.75 2.00 2.25 2.50 Tpeak (μs) 0.50

Spectroscopy

12.5



Fig. 2: In red, the legacy of IDeFX-HDBD ASIC and in green, new functions added designed by CEA-Irfu

PS2 is used for the main charge measurement on a 30 keV dynamic range.

SH is connected to G2 and is used to measure the common noise on all channels.

If one channel is hit (trigger flag) the global hold is going to be activated and the noise is sampled by all SH circuits.

The PS1 circuit is used only if the PS2 is saturated.

In this case the charge information is memorized by PS2 that has an 80 keV dynamic range.

Am ²⁴¹ 450 Test injection: 190 eV FWHM 22 el.rms 400 350 358 eV FWHM @ 13,94 keV 36 el.rms 300 Counts 220 474 eV FWHM @ 59,54 keV 150 34 el.rms 100 50 50 30 10 60 20 40 Energy [keV]

Fig. 7: Spectrum obtained by simulatenously illuminating the SDD with a ²⁴¹Am source and injecting a reference charge on the ASIC. Detector temperature ~35°C (leakage current around 25 pA).

CONCLUSIONS AND PERSPECTIVES

Daughter board

IDeF-X S front-end ASIC



Fig. 3: Electronic board with ASIC stand-alone (bottom side).



Fig. 4: Close-up of the board with the SDD glued on the top side and connected to the ASIC.

We designed a new ASIC IDeF-X S to fulfill the eXTP mission requirements for X-ray imaging spectroscopy with silicon detectors. We demonstrated a floor noise 13 electrons rms. The next step is spectroscopy in a vacuum chamber to cool down the detector to decrease the leakage current. The test set-up is in preparation.



Fig. 8: 3D view of the final assembly for spectral measurements



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